

MOSFET

OptiMOS™ 6 Power-Transistor, 150 V

Features

- N-channel, normal level
- Very low on-resistance R_{DS(on)}
- Superior thermal resistance
- 100% avalanche tested
- Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21
- MSL 1 classified according to J-STD-020

Product validation

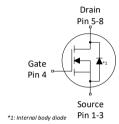
Fully qualified according to JEDEC for Industrial Applications

Table 1 Key Performance Parameters

Parameter	Value	Unit
$V_{ m DS}$	150	V
$R_{\mathrm{DS(on),max}}$	4.4	mΩ
I_{D}	156	А
$Q_{\rm oss}$	163	nC
Q_{G}	55	nC
Q _{rr} (500 A/μs)	137	nC









Type/Ordering Code	Package	Marking	Related Links
ISC044N15NM6	PG-TSON-8	04415N6	-

Public

OptiMOS™ 6 Power-Transistor, 150 V ISC044N15NM6



Table of Contents

Description	1
Maximum ratings	3
Thermal characteristics	3
Electrical characteristics	4
Electrical characteristics diagrams	6
Package Outlines	. 10
Revision History	. 13
Trademarks	. 13
Disclaimer	12



1 Maximum ratings

at T_A =25 °C, unless otherwise specified

Table 2 Maximum ratings

Davamakar	Cymahal		Values			Note / Took Condition
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Continuous drain current ¹⁾	I _D	-	-	156 111 103 17.1	A	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =8 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm A}$ =25 °C, $R_{\rm thJA}$ =50 °C/W ²⁾
Pulsed drain current ³⁾	I _{D,pulse}	-	-	624	А	<i>T</i> _c =25 °C
Avalanche current, single pulse ⁴⁾	I _{AS}	-	-	50	А	<i>T</i> _C =25 °C
Avalanche energy, single pulse	E _{AS}	-	-	1050	mJ	$I_{\rm D}$ =15 A, $R_{\rm GS}$ =25 Ω
Gate source voltage	V_{GS}	-20	-	20	V	-
Power dissipation	P_{tot}	-	-	250 3.0	W	$T_{\rm C}$ =25 °C $T_{\rm A}$ =25 °C, $R_{\rm thJA}$ =50 °C/W ²⁾
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-55	-	175	°C	-

¹⁾ Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.

2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	,	Values			Nieto/Tost Condition
raiailletei	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Thermal resistance, junction - case, bottom	R_{thJC}	-	-	0.59	°C/W	-
Thermal resistance, junction - case, top	R_{thJC}	-	-	20	°C/W	-
Thermal resistance, junction - ambient, 6 cm ² cooling area ⁵⁾	$R_{ m thJA}$	-	-	50	°C/W	-

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

²⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

³⁾ See Diagram 3 for more detailed information

⁴⁾ See Diagram 13 for more detailed information



3 Electrical characteristics

at $T_{\rm j}$ =25 °C, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition	
raiailletei	Syllibol	Min.	Тур.	Мах.	Ollic	Note/ Test Condition	
Drain-source breakdown voltage	$V_{(BR)DSS}$	150	-	-	V	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =1 mA	
Gate threshold voltage	$V_{\rm GS(th)}$	3.0	3.5	4.0	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 140 \mu \text{A}$	
Zero gate voltage drain current	I _{DSS}	-	0.1 10	1 100	μΑ	$V_{\rm DS}$ =120 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C $V_{\rm DS}$ =120 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C	
Gate-source leakage current	I_{GSS}	-	10	100	nA	$V_{\rm GS}$ =20 V, $V_{\rm DS}$ =0 V	
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	3.5 3.8 4.3	4.2 4.4 5.1	mΩ	V_{GS} =15 V, I_D =50 A V_{GS} =10 V, I_D =50 A V_{GS} =8 V, I_D =25 A	
Gate resistance	R_{G}	-	0.86	1.29	Ω	-	
Transconductance	g_{fs}	48	97	-	S	$ V_{\rm DS} \ge 2 I_{\rm D} R_{\rm DS(on)max}, I_{\rm D}=50 \text{ A}$	

Table 5 Dynamic characteristics

Daramatar	Symbol	Values			Unit	Note / Test Condition
Parameter	ter Symbol Min. Typ. Ma		Мах.	Onit	Note/ Test Condition	
Input capacitance ⁶⁾	C _{iss}	-	3900	5100	pF	V _{GS} =0 V, V _{DS} =75 V, <i>f</i> =1 MHz
Output capacitance ⁶⁾	C _{oss}	-	1200	1600	pF	V _{GS} =0 V, V _{DS} =75 V, <i>f</i> =1 MHz
Reverse transfer capacitance ⁶⁾	C _{rss}	-	16	24	pF	V _{GS} =0 V, V _{DS} =75 V, <i>f</i> =1 MHz
Turn-on delay time	$t_{\sf d(on)}$	-	15	-	ns	$V_{\rm DD}$ =75 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =25 A, $R_{\rm G,ext}$ =1. 6 Ω
Rise time	t _r	-	7	-	ns	$V_{\rm DD}$ =75 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =25 A, $R_{\rm G,ext}$ =1. 6 Ω
Turn-off delay time	$t_{\sf d(off)}$	-	20	-	ns	$V_{\rm DD}$ =75 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =25 A, $R_{\rm G,ext}$ =1. 6 Ω
Fall time	t _f	-	10	-	ns	$V_{\rm DD}$ =75 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =25 A, $R_{\rm G,ext}$ =1. 6 Ω

⁶⁾ Defined by design. Not subject to production test.



Table 6 Gate charge characteristics 7)

Parameter	Symbol	Values			l lmit	Note / Test Condition	
raiametei	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition	
Gate to source charge ⁸⁾	$Q_{ m gs}$	-	21	27	nC	$V_{\rm DD}$ =75 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 10 V	
Gate charge at threshold	$Q_{\mathrm{g(th)}}$	-	13.6	-	nC	$V_{\rm DD}$ =75 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 10 V	
Gate to drain charge ⁸⁾	$Q_{ m gd}$	-	12.5	18.8	nC	$V_{\rm DD}$ =75 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 10 V	
Switching charge	Q_{sw}	-	19.5	-	nC	$V_{\rm DD}$ =75 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 10 V	
Gate charge total ⁸⁾	Q_{g}	-	55	72	nC	$V_{\rm DD}$ =75 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 10 V	
Gate plateau voltage	$V_{ m plateau}$	-	5.3	-	V	$V_{\rm DD}$ =75 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 10 V	
Gate charge total, sync. FET	$Q_{g(sync)}$	-	46	-	nC	$V_{\rm DS}$ =0.1 V, $V_{\rm GS}$ =0 to 10 V	
Output charge ⁸⁾	$Q_{ m oss}$	-	163	212	nC	V _{DS} =75 V, V _{GS} =0 V	

 $^{^{7)} \;\;}$ See "Gate charge waveforms" for parameter definition

Table 7 Reverse diode

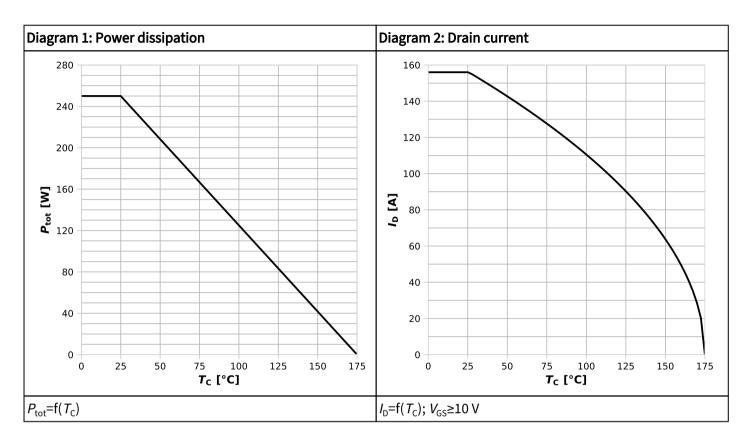
Parameter	Symbol	Values			Unit	Note/ Test Condition	
raiailletei	Symbol	Min.	Тур.	Max.	Oilit	Note/ Test Condition	
Diode continuous forward current	Is	-	-	156	А	<i>T</i> _c =25 °C	
Diode pulse current	I _{S,pulse}	-	-	624	А	<i>T</i> _c =25 °C	
Diode forward voltage	$V_{\rm SD}$	-	0.83	1.0	V	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =50 A, $T_{\rm j}$ =25 °C	
Reverse recovery time ⁹⁾	t _{rr}	-	33	66	ns	$V_{\rm R}$ =75 V, $I_{\rm F}$ =25 A, d $i_{\rm F}$ /d t =500 A/ μ s	
Reverse recovery charge ⁹⁾	$Q_{\rm rr}$	-	137	274	nC	$V_{\rm R}$ =75 V, $I_{\rm F}$ =25 A, d $i_{\rm F}$ /d t =500 A/ μ s	
Reverse recovery time ⁹⁾	t _{rr}	-	29	58	ns	$V_{\rm R}$ =75 V, $I_{\rm F}$ =25 A, d $i_{\rm F}$ /d t =1000 A/ μ s	
Reverse recovery charge ⁹⁾	$Q_{\rm rr}$	_	274	548	nC	$V_{\rm R}$ =75 V, $I_{\rm F}$ =25 A, d $i_{\rm F}$ /d t =1000 A/ μ s	

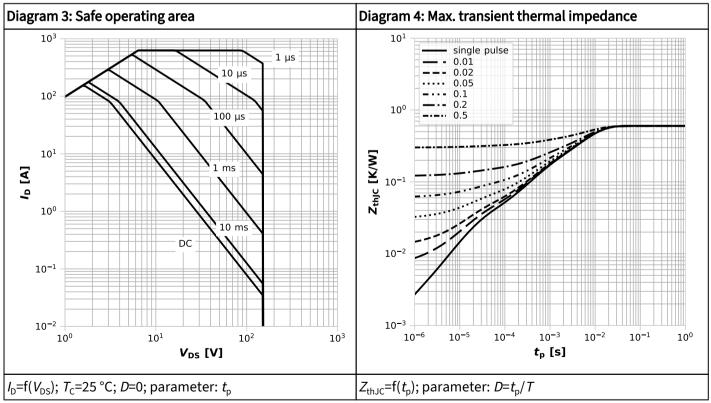
⁹⁾ Defined by design. Not subject to production test.

⁸⁾ Defined by design. Not subject to production test.

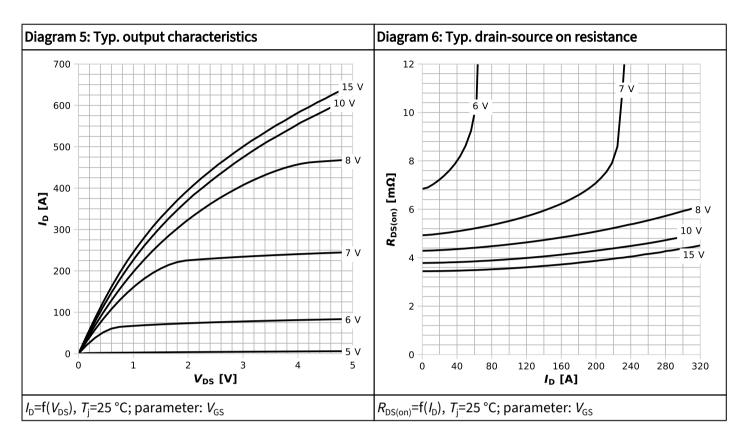


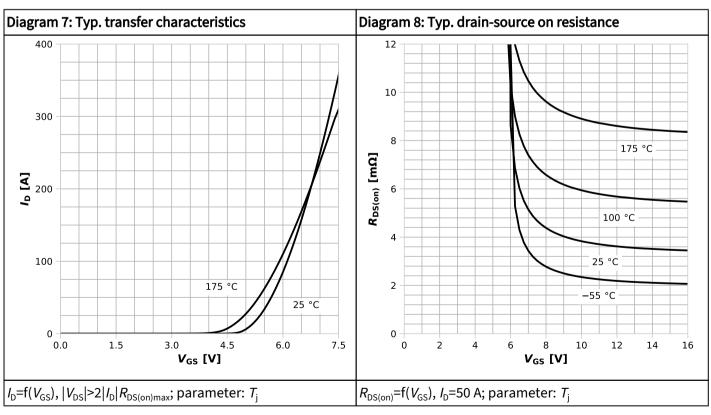
4 Electrical characteristics diagrams



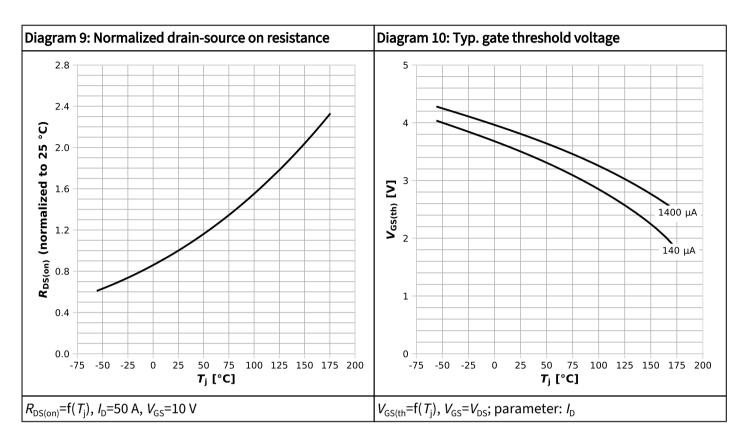


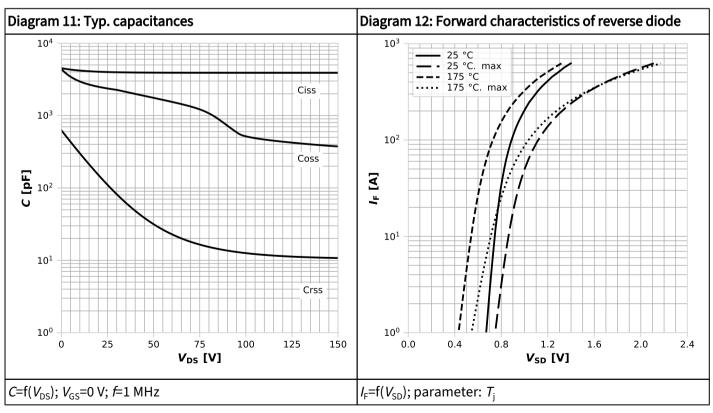




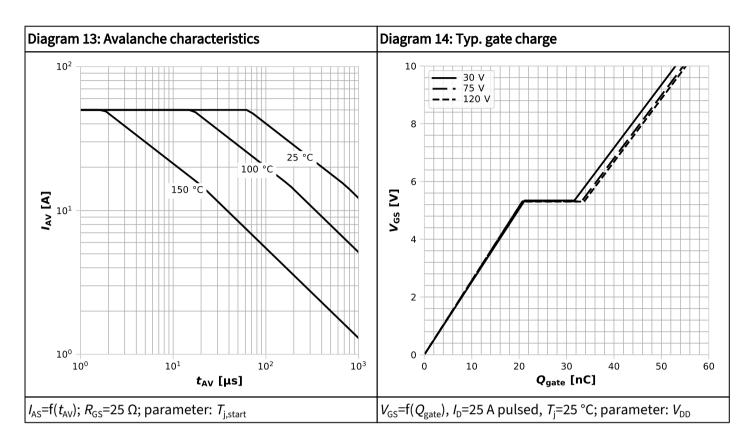


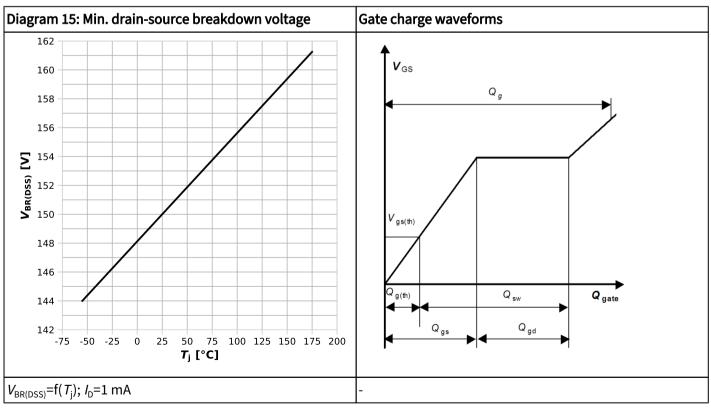






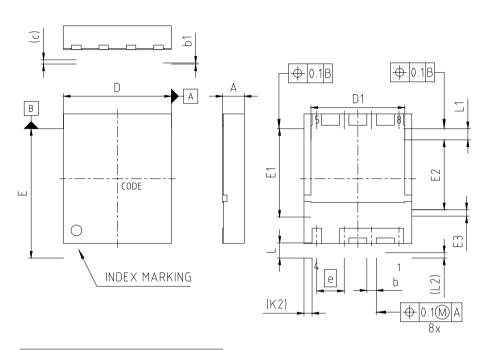








5 Package Outlines



PACKAGE - GROUP NUMBER:	PG-TSON-8-U05						
DIMENSION	MILLIMETERS						
DINENSION	MIN.	MAX.					
Α	0.90	1.10					
b	0.34	0.54					
b1	0.00	0.05					
С	0.20						
D	4.90	5.10					
D1	4.25	4.45					
E	5.90	6.10					
E1	4.00	4.20					
E2	3.14	3.34					
E3	0.20	0.40					
е	1.2	27					
K2	0.38						
L	0.60 0.80						
L1	0.43	0.63					
L2	0.2	25					

NOTE: DIMENSIONS DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS

Figure 1 Outline PG-TSON-8, dimensions in mm



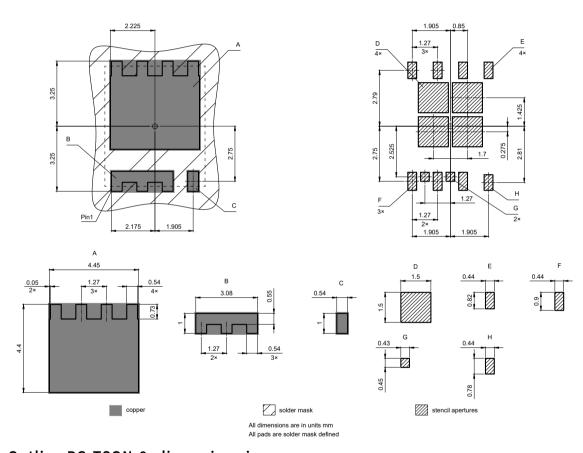


Figure 2 Outline PG-TSON-8, dimensions in mm



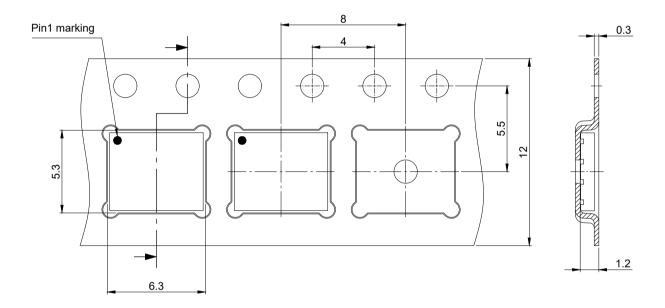


Figure 3 Outline PG-TSON-8, dimensions in mm



Revision History

ISC044N15NM6

Revision 2024-04-24, Rev. 2.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)
1.0	2024-03-15	Release of preliminary version
2.0	2024-04-24	Release of final

Trademarks

All referenced product or service names and trademarks are the property of their respective owners.

We Listen to Your Comments Any information within this document that you feel is wrong, unclear or missing at all? Your feedback will help us to continuously improve the quality of this document. Please send your proposal (including a reference to this document) to: erratum@infineon.com

Published by Infineon Technologies AG 81726 München, Germany © 2024 Infineon Technologies AG All Rights Reserved.

Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office (www. infineon.com).

Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

The Infineon Technologies component described in this Data Sheet may be used in life-support devices or systems and/or automotive, aviation and aerospace applications or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support, automotive, aviation and aerospace device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.